

PATENT APPLICATION

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of

Mari SUGIHARA et al.

Application No.: New U.S. Patent Application

Filed: March 22, 2004

Docket No.: 119182

For: DEFECT INSPECTION APPARATUS, DEFECT INSPECTION METHOD AND
METHOD OF INSPECTING HOLE PATTERN

PRELIMINARY AMENDMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

Please consider the following:

Amendments to the Claims as reflected in the listing of claims;

Remarks.